

**TOSHIBA**

**1S1830, 1S1885, 1S1887, 1S1888**

TOSHIBA RECTIFIER SILICON DIFFUSED TYPE

# 1S1830, 1S1885, 1S1887, 1S1888

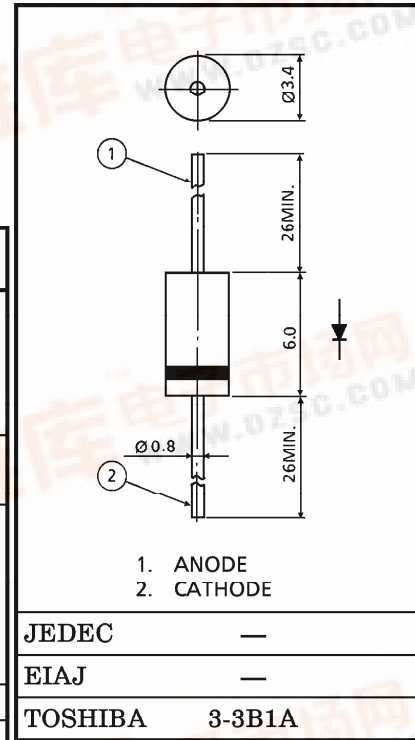
GENERAL PURPOSE RECTIFIER APPLICATIONS.

Unit in mm

- Average Forward Current :  $I_F (AV) = 1.0A$  ( $T_a = 65^\circ C$ )
- Repetitive Peak Reverse Voltage :  $V_{RRM} = 100 \sim 1000V$

MAXIMUM RATINGS ( $T_a = 25^\circ C$ )

CHARACTERISTIC	SYMBOL	RATINGS	UNIT
Repetitive Peak Reverse Voltage	1S1885	100	V
	1S1887	400	
	1S1888	600	
	1S1830	1000	
Average Forward Current ( $T_a = 65^\circ C$ )	$I_F (AV)$	1.0	A
Peak One Cycle Surge Forward Current (Non Repetitive)	1S1830	45 (50Hz)	A
	1S1885	49 (60Hz)	
	1S1887	60 (50Hz)	
	1S1888	66 (60Hz)	
Junction Temperature	$T_j$	$-40 \sim 150$	$^\circ C$
Storage Temperature Range	$T_{stg}$	$-40 \sim 150$	$^\circ C$

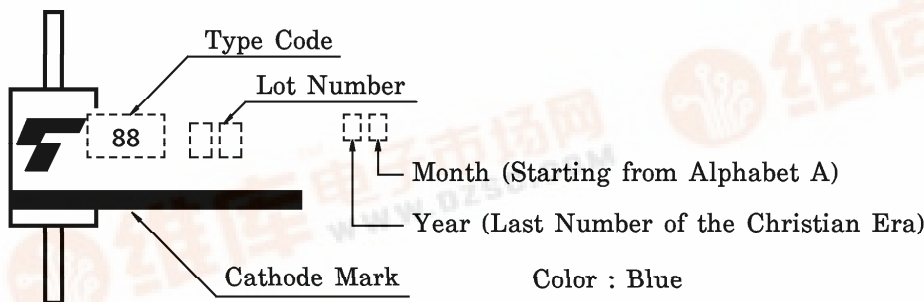


Weight : 0.42g

ELECTRICAL CHARACTERISTICS ( $T_a = 25^\circ C$ )

CHARACTERISTIC	SYMBOL	TEST CONDITION	MIN.	TYP.	MAX.	UNIT
Peak Forward Voltage	$V_{FM}$	$I_{FM} = 1.5A$	—	—	1.2	V
Repetitive Peak Reverse Current	$I_{RRM} (1)$	$V_{RRM} = \text{Rated}$	—	—	10	$\mu A$
	$I_{RRM} (2)$	$V_{RRM} = \text{Rated}, T_j = 150^\circ C$	—	—	400	
Thermal Resistance (Junction to Ambient)	$R_{th(j-a)}$	DC	—	—	100	$^\circ C / W$

MARK



CODE	TYPE
30	1S1830
85	1S1885
87	1S1887
88	1S1888

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TOSHIBA is continually working to improve the quality and the reliability of its products. Nevertheless, semiconductor devices in general can malfunction or fail due to their inherent electrical sensitivity and vulnerability to physical stress. It is the responsibility of the buyer, when utilizing TOSHIBA products, to observe standards of safety, and to avoid situations in which a malfunction or failure of a TOSHIBA product could cause loss of human life, bodily injury or damage to property. In developing your designs, please ensure that TOSHIBA products are used within specified operating ranges as set forth in the most recent products specifications. Also, please keep in mind the precautions and conditions set forth in the TOSHIBA Semiconductor Reliability Handbook.

